



PI74ALVTC16260

2.5V 12-Bit to 24-Bit Multiplexed D-Type Latch with 3-State Outputs

**Product Features**

- PI74ALVTC16260 is designed for low voltage operation,  $V_{DD}=1.65V$  to  $3.6V$
- Supports Live Insertion
- 3.6V I/O Tolerant Inputs and Outputs
- Bus Hold
- High Drive,  $-32/64mA @ 3.3V$
- Uses patented noise reduction circuitry
- Power-off high impedance inputs and outputs
- Industrial operation at  $-40^{\circ}C$  to  $+85^{\circ}C$
- Packages available:
  - 56-pin 240-mil wide plastic TSSOP (A56)
  - 56-pin 173-mil wide plastic TVSOP (K56)

**Product Description**

Pericom Semiconductor’s PI74ALVTC series of logic circuits are produced using the Company’s advanced 0.35 micron CMOS technology, achieving industry leading speed.

The PI74ALVTC16260 is a 12-bit to 24-bit multiplexed D-type latch designed for 1.65V to 3.6V  $V_{DD}$  operation. It is used in applications where two separate datapaths must be multiplexed onto, or demultiplexed from, a single data path.

Typical applications include multiplexing and/or demulti-plexing address and data information in microprocessor or bus-interface applications. This device is also useful in memory-interleaving applications.

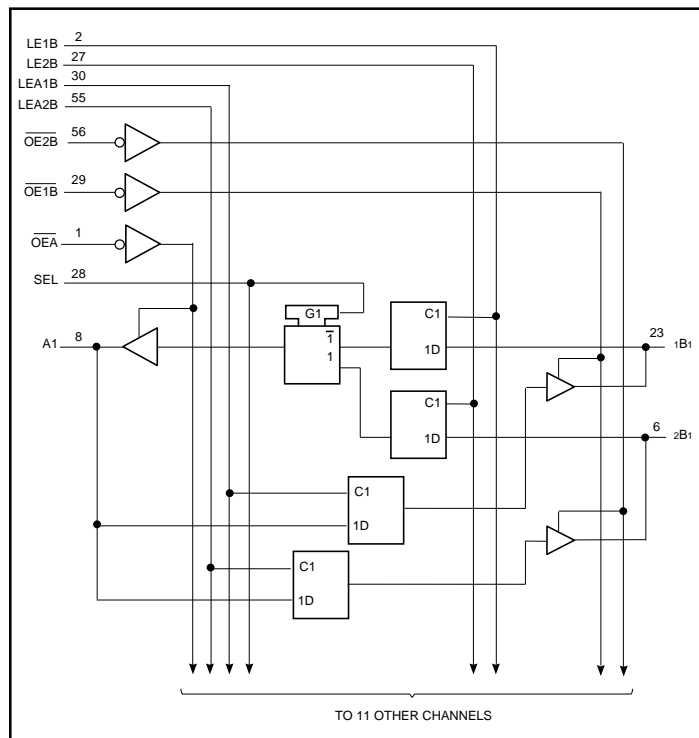
Three 12-bit I/O ports (A1-A12, 1B1-1B12, and 2B1-2B12) are available for address and/or data transfer. The output-enable ( $\overline{OE1B}$ ,  $\overline{OE2B}$ , and  $\overline{OE A}$ ) inputs control the bus transceiver functions. The  $\overline{OE1B}$  and  $\overline{OE2B}$  control signals also allow bank control in the A-to-B direction.

Address and/or data information can be stored using the internal storage latches. The latch-enable ( $\overline{LE1B}$ ,  $\overline{LE2B}$ ,  $\overline{LEA1B}$ , and  $\overline{LEA2B}$ ) inputs are used to control data storage. When the latch-enable input is HIGH, the latch is transparent. When the latch-enable input goes LOW, the data present at the inputs is latched and remains latched until the latch-enable input is returned HIGH.

To ensure the high-impedance state during power up or power down, OE should be tied to  $V_{DD}$  through a pullup resistor, the minimum value of the resistor is determined by the current-sinking capability of the driver.

The family offers both I/O Tolerant, which allows it to operate in mixed 1.65/3.6V systems, and “Bus Hold,” which retains the data input’s last state preventing “floating” inputs and eliminating the need for pullup/down resistors.

**Logic Block Diagram**





**Product Pin Description**

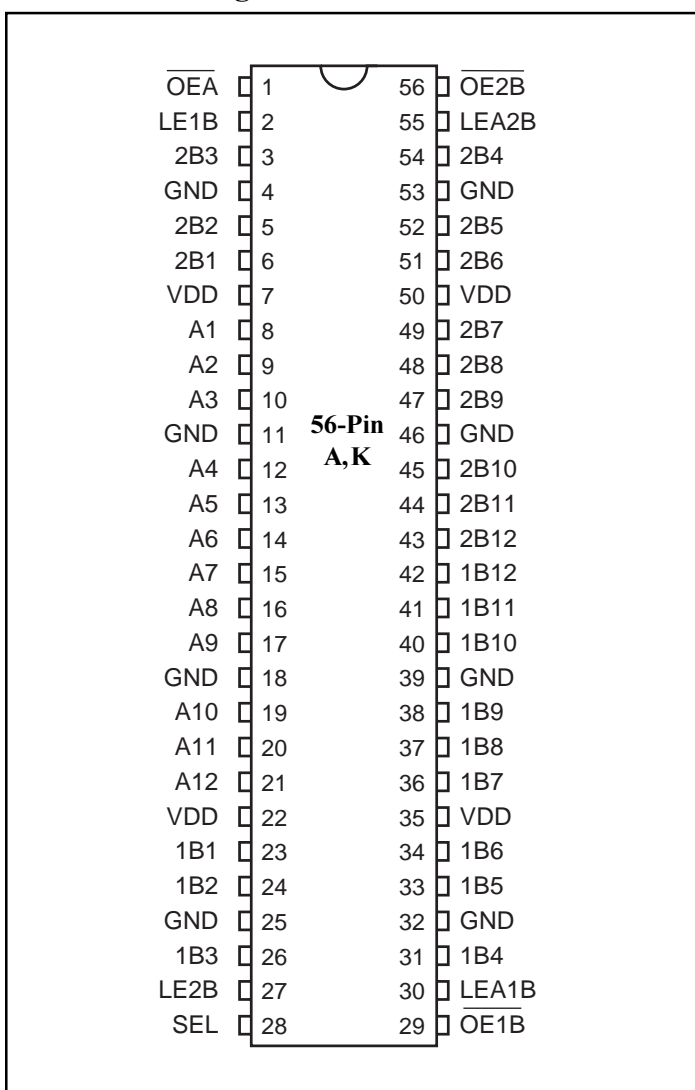
Pin Name	Description
$\overline{OE}$	Output Enable Input (Active LOW)
SEL	Select
LE	Latch Enable
A,1B,2B	Data Inputs
A,1B,2B	3-State Outputs
GND	Ground
V <sub>DD</sub>	Power

**Truth Tables<sup>(1)</sup>**

**B to A ( $\overline{OE} = H$ )**

Inputs						Output A
1B	2B	SEL	LE1B	LE2B	$\overline{OE}A$	
H	X	H	H	X	L	H
L	X	H	H	X	L	L
X	X	H	L	X	L	A0
X	H	L	X	H	L	H
X	L	L	X	H	L	L
X	X	L	X	L	L	A0
X	X	X	X	X	H	Z

**Product Pin Configuration**



**A to B ( $\overline{OE} = H$ )**

INPUTS					OUTPUTS	
A	LEA1B	LEA2B	$\overline{OE}1B$	$\overline{OE}2B$	1B	2B
H	H	H	L	L	H	H
L	H	H	L	L	L	L
H	H	L	L	L	H	2B0
L	H	L	L	L	L	2B0
H	L	H	L	L	1B0	H
L	L	H	L	L	1B0	L
X	L	L	L	L	1B0	2B0
X	X	X	H	H	Z	Z
X	X	X	L	H	Active	Z
X	X	X	H	L	Z	Active
X	X	X	L	L	Active	Active

**Note:**

- H = High Signal Level  
L = Low Signal Level  
X = Irrelevant  
Z = High Impedance

**Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Supply Voltage Range, $V_{DD}$ .....	-0.5V to 4.6V
Input Voltage Range, $V_I$ .....	-0.5V to 4.6V
Output Voltage Range, $V_O$ (3-States) .....	-0.5V to 4.6V
Output Voltage Range, $V_O^{(1)}$ (Active) .....	-0.5V to $V_{DD}+0.5V$
DC Input Diode Current ( $I_{IK}$ ) $V_I < 0V$ .....	-50mA
DC Output Diode Current ( $I_{OK}$ )	
$V_O < 0V$ .....	-50mA
$V_O > V_{DD}$ .....	$\pm 50mA$
DC Output Source/Sink Current ( $I_{OH}/I_{OL}$ ) .....	-4/128mA
DC $V_{DD}$ or GND Current per Supply Pin ( $I_{CC}$ or GND) .....	$\pm 100mA$
Storage Temperature Range, $T_{stg}$ .....	-65°C to 150°C

**Note:**

Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

**Recommended Operating Conditions<sup>(2)</sup>**

			Min.	Max.	Units
$V_{DD}$	Supply voltage	Operating	1.65	3.6	V
		Data Retention Only	1.2	3.6	
$V_{IH}$	High-level input voltage	$V_{DD} = 2.7V$ to $3.6V$	2.0		
$V_{IL}$	Low-level input voltage	$V_{DD} = 2.7V$ to $3.6V$		0.8	
$V_I$	Input voltage		-0.3	3.6	
$V_O$	Output voltage	Active State	0	$V_{DD}$	
		Off State	0	3.6	
	Output current in $I_{OH}/I_{OL}$	$V_{DD} = 3.0V$ to $3.6V$ $V_{DD} = 3.0V$ to $3.6V$ $V_{DD} = 2.3V$ to $2.7V$ $V_{DD} = 1.65V$ to $1.95V$		-32/64 $\pm 24$ $\pm 18$ $\pm 6$	mA
$\Delta t/\Delta v$	Input transition rise or fall rate <sup>(3)</sup>		0	10	ns/V
$T_A$	Operating free-air temperature		-40	85	C

**Notes:**

1. Absolute maximum of  $I_O$  must be observed.
2. Unused control inputs must be held HIGH or LOW to prevent them from floating.
- 3 As measured between 0.8V and 2.0V,  $V_{DD} = 3.0V$ .

**Electrical Characteristics over Recommended Operating Free-Air Temperature Range**  
(unless otherwise noted)

**DC Characteristics (2.7V <math>V\_{DD}</math> ≤ 3.6V)**

	Parameter	Conditions	$V_{DD}$	Min.	Typ.	Max.	Units
$V_{IK}$	Input Clamp Diode	$I_{IK} = -18\text{mA}$	3.0			-1.2	V
$V_{OH}$	HIGH Level Output Voltage	$I_{OH} = -100\mu\text{A}$	2.7 - 3.6	$V_{DD} - 0.2$			
		$I_{OH} = -12\text{mA}$	2.7	2.2			
		$I_{OH} = -18\text{mA}$	3.0	2.4			
		$I_{OH} = -24\text{mA}$		2.2			
		$I_{OH} = -32\text{mA}$		2.0			
$V_{OL}$	LOW Level Output Voltage	$I_{OL} = 100\mu\text{A}$	2.7 - 3.6			0.2	
		$I_{OL} = 12\text{mA}$	2.7			0.4	
		$I_{OL} = 18\text{mA}$	3.0			0.4	
		$I_{OL} = 24\text{mA}$		0.45			
		$I_{OL} = 32\text{mA}$		0.5			
		$I_{OL} = 64\text{mA}$		0.55			
$I_I$	Input Leakage Current	$V_I = V_{DD}$ , or GND	3.6			±5.0	μA
$I_{OZ}$	3-State Output Leakage	$V_O = 3.6\text{V}$	2.7			±10	
$I_{OFF}$	Power-OFF Leakage Current	$V_I$ or $V_O \leq 3.6\text{V}$	0			10	
$I_{HOLD}$	Bus Hold Current A or B Outputs	$V_I = 0.8\text{V}$	3.0	75			
		$V_I = 2.0\text{V}$		-75			
		$V_I = 0$ to $3.6\text{V}$	3.6			±500	
$I_{DD}$	Quiescent Supply Current	$V_I = V_{DD}$ or GND	2.7 - 3.6			50	
		$V_{DD} \leq (V_I, V_O) \leq 3.6\text{V}$				±50	
$\Delta I_{DD}$	Increase in $I_{DD}$ per input	$V_{IH} = V_{DD} - 0.6\text{V}$ , Other inputs at $V_{DD}$ or Gnd				400	



**Electrical Characteristics over Recommended Operating Free-Air Temperature Range**

(unless otherwise noted; continued from previous page)

**DC Characteristics ( $2.3V \leq V_{DD} \leq 2.7V$ )**

Description	Parameters	Conditions	V <sub>DD</sub>	Min.	Typ.	Max.	Units
V <sub>IK</sub>	Input Clamp Diode	I <sub>IK</sub> = -18mA	2.3			-1.2	V
V <sub>OH</sub>	HIGH Level Output Voltage	I <sub>OH</sub> = -100μA	2.3 - 2.7	V <sub>DD</sub> - 0.2			
		I <sub>OH</sub> = -12mA	2.3	1.8			
		I <sub>OH</sub> = -18mA		1.7			
V <sub>OL</sub>	LOW Level Output Voltage	I <sub>OL</sub> = 100μA	2.3 - 2.7			0.2	
		I <sub>OL</sub> = 12mA	2.3			0.4	
		I <sub>OL</sub> = 18mA				0.5	
		I <sub>OL</sub> = 24mA				0.55	
I <sub>I</sub>	Input Leakage Current	V <sub>I</sub> = V <sub>DD</sub> or GND	2.7			±5.0	μA
I <sub>OZ</sub>	3-State Output Leakage	V <sub>O</sub> = 3.6V	2.3			±10	
I <sub>OFF</sub>	Power-OFF Leakage Current	V <sub>I</sub> or V <sub>O</sub> ≤ 3.6V	0			10	
I <sub>HOLD</sub> <sup>(1)</sup>	Bus Hold Current A or B Outputs	V <sub>I</sub> = 0.7V	2.5		90		μA
		V <sub>I</sub> = 1.7V			-90		
I <sub>DD</sub>	Quiescent Supply Current	V <sub>I</sub> = V <sub>DD</sub> or GND	2.3 - 2.7			40	μA
		V <sub>DD</sub> ≤ (V <sub>I</sub> , V <sub>O</sub> ) ≤ 3.6V				±40	
ΔI <sub>DD</sub>	Increase in I <sub>DD</sub> per input	V <sub>IH</sub> = V <sub>DD</sub> - 0.6V, Inputs at V <sub>DD</sub> or Gnd					

**Note:**

1. Not Guaranteed

**Electrical Characteristics over Recommended Operating Free-Air Temperature Range**

(unless otherwise noted; continued from previous page)

**DC Characteristics ( $1.65V \leq V_{DD} \leq 1.95V$ )**

Description	Parameters	Conditions	$V_{DD}$	Min.	Typ.	Max.	Units
$V_{IK}$	Input Clamp Diode	$I_{IK} = -18mA$	1.65			-1.2	V
$V_{OH}$	HIGH Level Output Voltage	$I_{OH} = -100\mu A$	1.65-1.95	$V_{DD} - 0.2$			
		$I_{OH} = -6mA$		1.4			
$V_{OL}$	LOW Level Output Voltage	$I_{OL} = 100\mu A$	1.65			0.2	
		$I_{OL} = 6mA$				0.3	
$I_I$	Input Leakage Current	$V_I = V_{DD}$ or GND	1.95			$\pm 5.0$	$\mu A$
$I_{OZ}$	3-State Output Leakage	$V_O = 3.6V$	1.65			$\pm 10$	
$I_{OFF}$	Power-OFF Leakage Current	$V_I = V_O \leq 3.6V$	0			10	
$I_{HOLD}^{(1)}$	Bus Hold Current A or B Outputs	$V_I = 0.4$	1.65		50		
		$V_I = 1.3$			-50		
$I_{DD}$	Quiescent Supply Current	$V_I = V_{DD}$ or GND	1.65-1.95			20	
		$V_{DD} \leq (V_I, V_O) \leq 3.6V$				$\pm 20$	
$\Delta I_{DD}$	Increase in $I_{DD}$ per input	$V_I = V_{DD} - 0.6V$ , Other inputs at $V_{DD}$ or Gnd				400	

**Note:**

1. Not Guaranteed

**Timing Requirements over recommended operating free-air temperature range**  
(unless otherwise noted, see Figure 1 thru 4)

		V <sub>DD</sub> = 1.8V ± 0.15V		V <sub>DD</sub> = 2.5V ± 0.2V		V <sub>DD</sub> = 3.3V ± 0.3V		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>w</sub>	Pulse duration, LE1B, LE2B, LEA1B, or LEA2B High			3.3		3.3		ns
t <sub>su</sub>	Setup time, data before LE1B, LE2B, LEA1B, or LEA2B			1.0		1.0		
t <sub>h</sub>	Hold time, data after LE1B, LE2B, LEA1B, or LEA2B			1.0		1.0		

**Switching Requirements over recommended operating free-air temperature range**  
(unless otherwise noted, see Figure 1 thru 4)

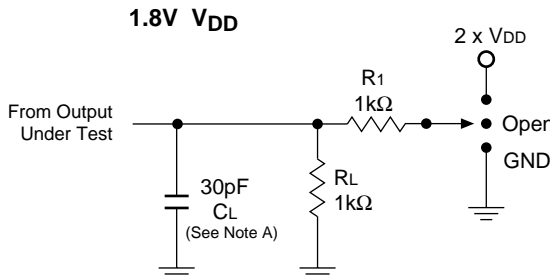
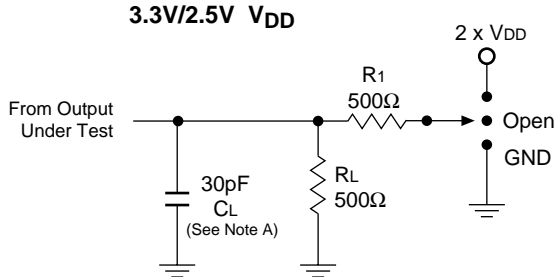
Parameter	From (Input)	To (Output)	V <sub>DD</sub> = 1.8V ± 0.15V		V <sub>DD</sub> = 2.5V ± 0.2V		V <sub>DD</sub> = 3.3V ± 0.3V		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>pd</sub>	A or B	B or A			1.0	5.3	1.0	4.6	ns
	LE	A or B			1.1	6.0	1.1	4.6	
	$\overline{\text{SEL}}$	A			1.6	4.5	1.6	3.4	
t <sub>en</sub>	$\overline{\text{OE}}$	A or B			1.6	5.0	1.6	4.0	
t <sub>dis</sub>	$\overline{\text{OE}}$	A or B			2.2	6.5	2.2	5.0	

**Operating Characteristics, T<sub>A</sub> = 25°C**

Parameter		Test Conditions	V <sub>DD</sub> = 2.5V ± 0.2V	V <sub>DD</sub> = 3.3V ± 0.3V	Units
			Typical		
C <sub>pd</sub> Power Dissipation Capacitance	Outputs Enabled	C <sub>L</sub> = 50pF, f = 10 MHz	TBD	TBD	pF
	Outputs Disabled		TBD	TBD	

Test Circuits and Switching Waveforms

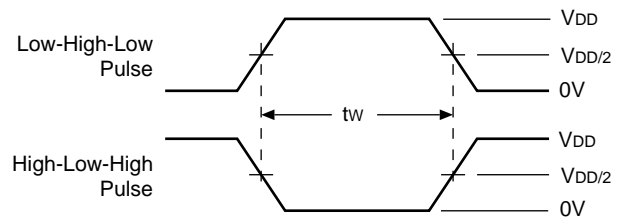
Parameter Measurement Information ( $V_{DD} = 1.65V - 3.6V$ )



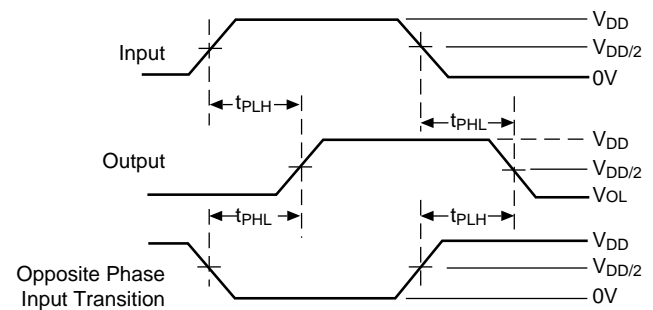
Switch Position

Test	S1
$t_{PD}$	Open
$t_{PLZ}/t_{PZL}$	$2 \times V_{DD}$
$t_{PHZ}/t_{PZH}$	GND

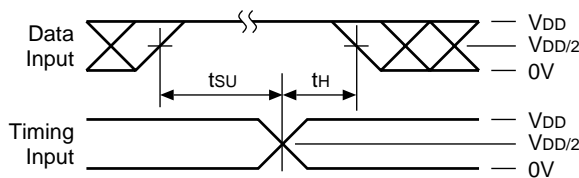
Pulse Width



Propagation Delay



Setup, Hold, and Release Timing



Notes:

- A.  $C_L$  includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is LOW except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is HIGH except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50\Omega$ ,  $t_r \leq 2\text{ns}$ ,  $t_f \leq 2\text{ns}$ , **measured from 10% to 90%, unless otherwise specified.**
- D. The outputs are measured one at a time with one transition per measurement.

Enable Disable Timing

